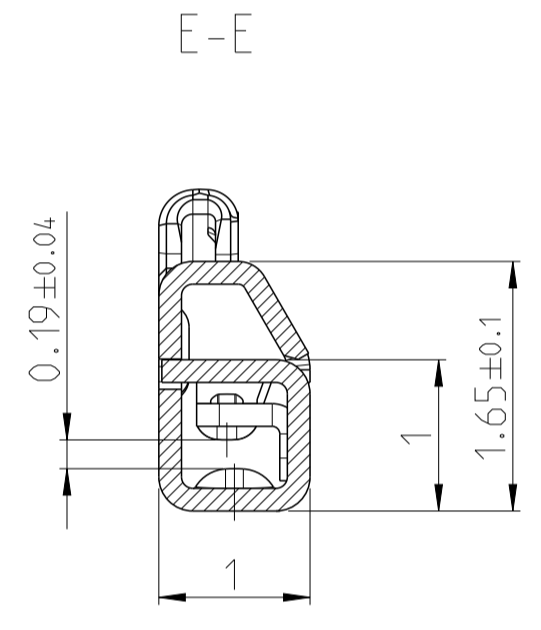
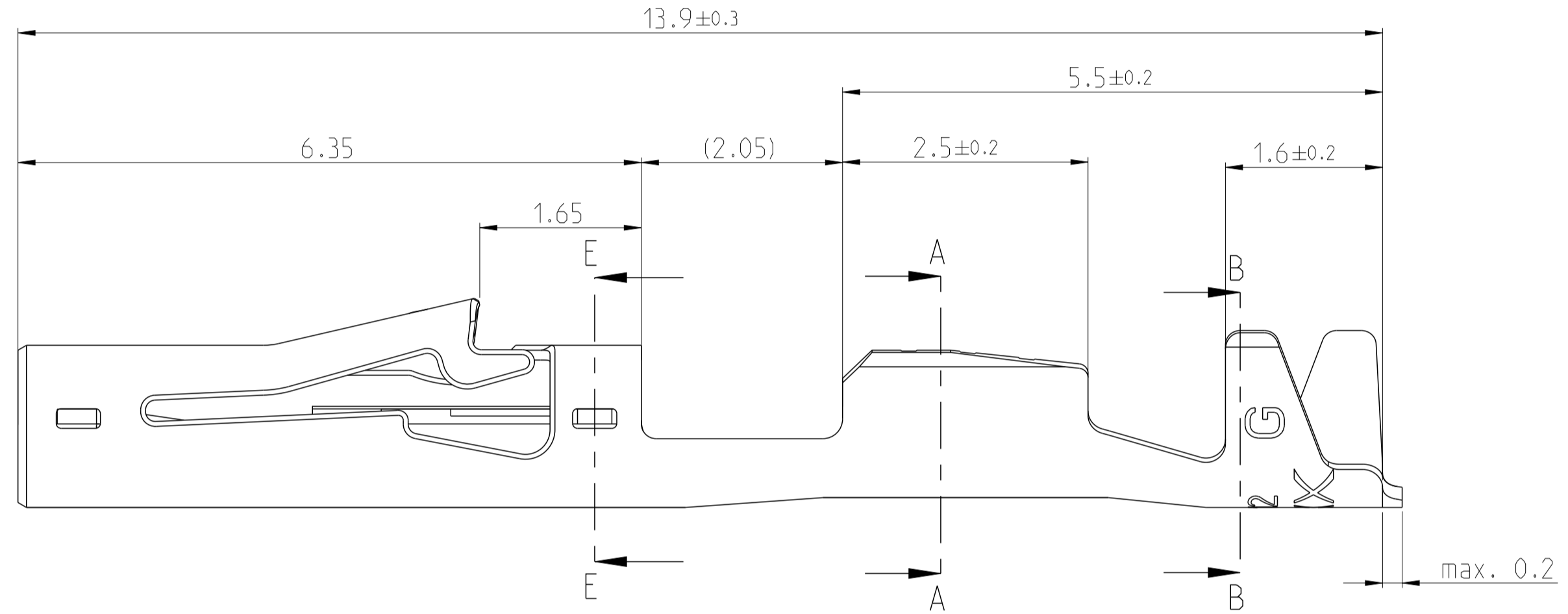
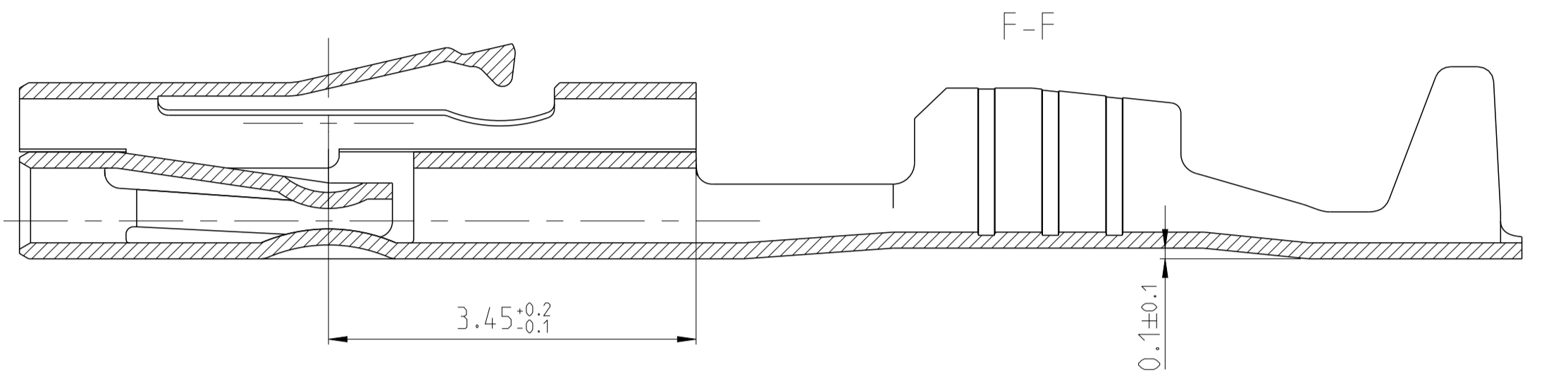
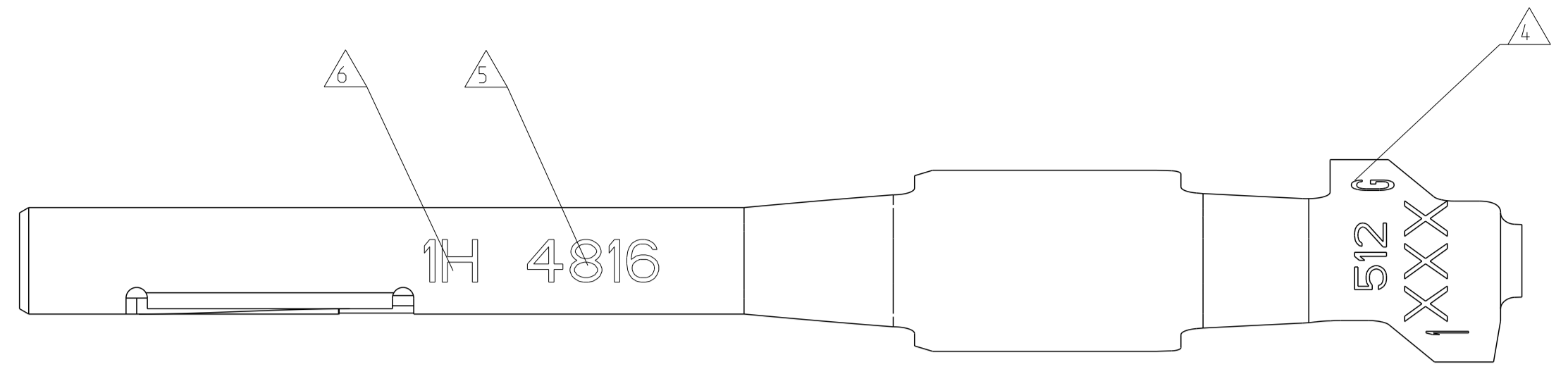
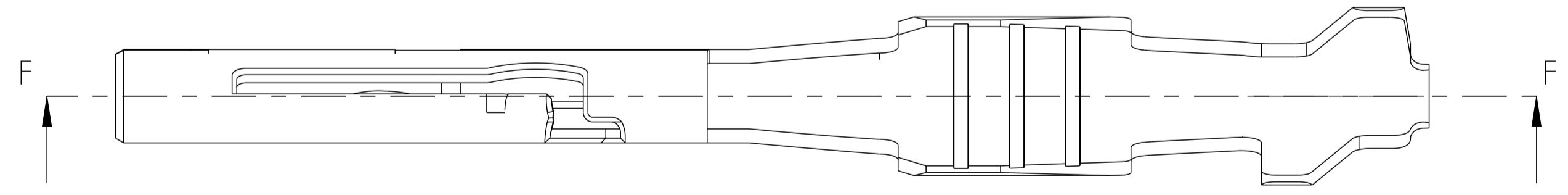
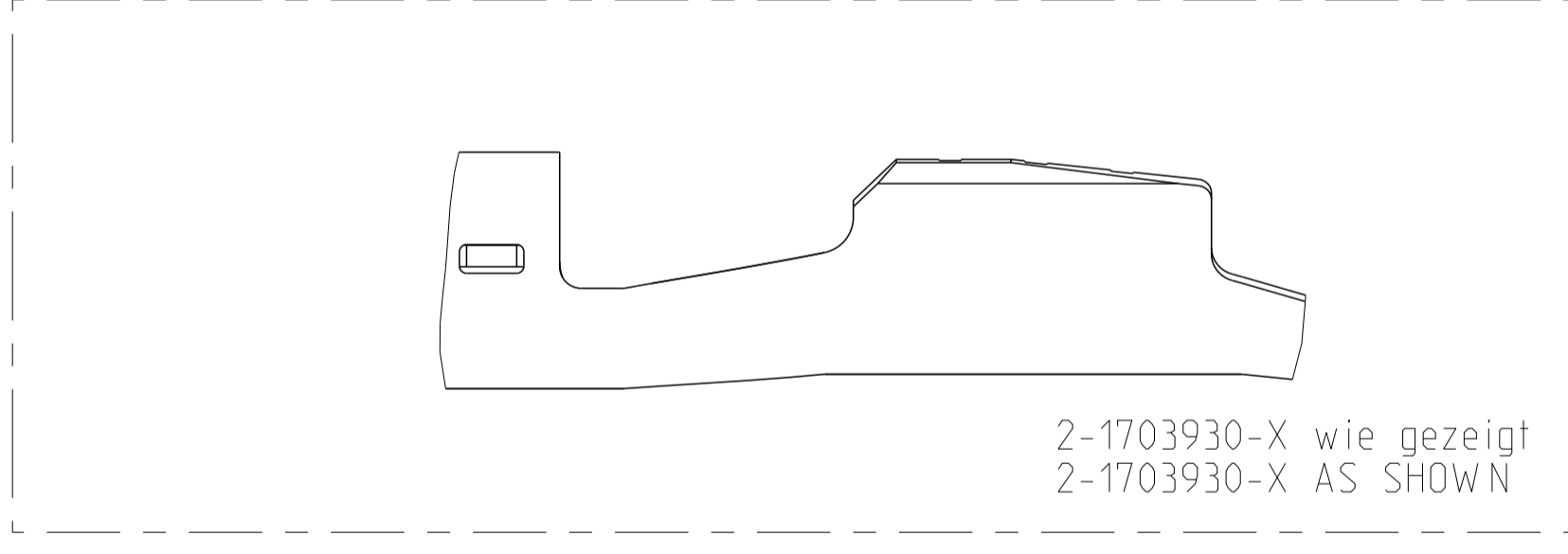
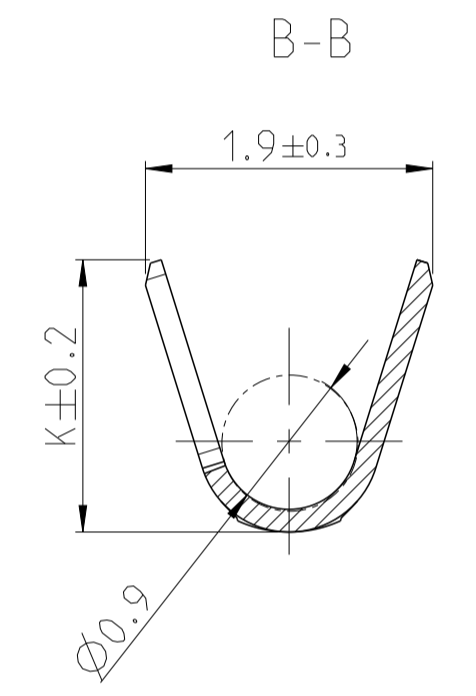
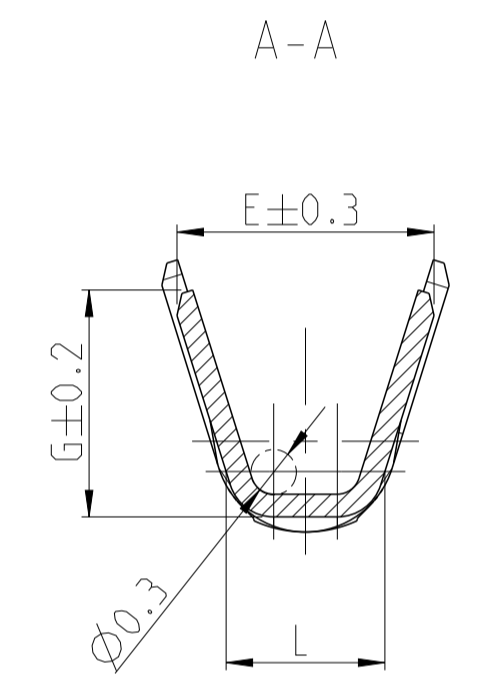
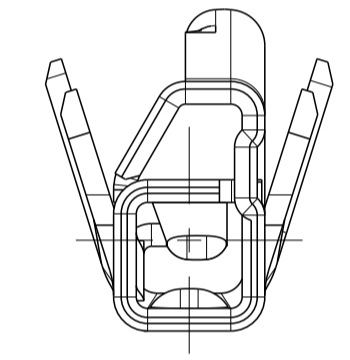


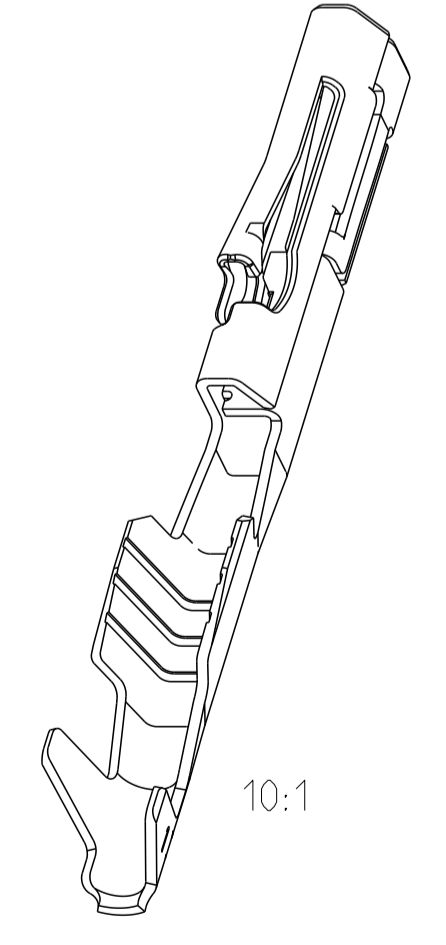
LOC	DIST	REVISIONS			
A1	-	REV.	DATE	BY	APPV
		E1	160C12012	MS	RJ
		E2	04JUL2013	MS	RJ
		F	21JAN2016	HD.	LEIM
		G	25NOV2016	HD.	LEIM



- Bemerkungen**
NOTES
- 1 Massgebend ist der deutsche Text
ONLY THE GERMAN LANGUAGE VERSION SHALL BE BINDING
 - 2 Einzelheiten der Ausführung bleiben dem Hersteller ueberlassen
DETAILS OF DESIGN ARE LEFT TO MANUFACTURER
 - 3 Passend zu Kontaktsliff: TE 114-94201
SUITABLE TO CONTACT-PIN.
- ⚠ TE-Revision
TE REVISION
- 📅 Datumscode (Woche/Jahr)
DATE-CODE (WEEK/YEAR)



1 Buchsenkontakt/SOCKET CONTACT
 Material: siehe Tabelle/SEE CHART
 Oberflaeche im Kontaktpunkt / SURFACE AT CONTACT-AREA:
 Sn: 0.8 ... 2.2 µm Sn
 Ag: 1.6 ... 5 µm Ag



TE BESTELL-NR. ORDER NO.	REV.	VERSION	Markierung MARKING	DGB WIRE SIZE RANGE [mm ²]	Material	OBERFLAECHE SURFACE	Gewicht WEIGHT [g]	Drahtcrimp WIRE CRIMP	Iso' crimp INSULATION CRIMP
2-1703930-2	G	HIGH PERFORMANCE	2H	0.22...0.35	CuNiSi	Ag	0.08	E = 1.7 G = 1.5 L = 1.05	K = 1.9
2-1703930-1	F	Standard	2		CuSn8	Sn			
1-1703930-2	F	HIGH PERFORMANCE	1H	0.13...0.17	CuNiSi	Ag	0.08	E = 1.6 G = 1.25 L = 0.9	K = 1.8
1-1703930-1	E	Standard	1		CuSn8	Sn			

THIS DRAWING IS A CONTROLLED DOCUMENT.		DWN S. G.	04SEP2007	TE Connectivity
DIMENSIONS: MASSENHEITEN (mm) TOLERANCES: UNLESS OTHERWISE SPECIFIED: ALL DIMENSIONS		CHK C. Boemmel	04SEP2007	
MATERIAL: - FINISH/OBERFLAECHE/FARB: -		APVD D. Jetter	04SEP2007	NAME: NanoMQS Buchsenkontakt SOCKET CONTACT SIZE: A1 CAGE CODE: 00779 DRAWING NO.: 1703930
WEIGHT: - GEWICHT: -		PRODUCT SPEC: 108-94099 APPLICATION SPEC: 114-10858 VERABREITUNGSSTREIFEN: 114-10858	SCALE: 20:1 SHEET: 1 OF 1 REV: G	

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[2-1703930-1](#)